

±2.5V to ±17V

0.00003% (typ)

0.00003% (typ)

±20V/µs (typ)

55MHz (typ)

140dB (typ)

0.000009%

LME49740 Quad High Performance, High Fidelity Audio Operational Amplifier

General Description

The LME49740 is part of the ultra-low distortion, low noise, high slew rate operational amplifier series optimized and fully specified for high performance, high fidelity applications. Combining advanced leading-edge process technology with state-of-the-art circuit design, the LME49740 audio operational amplifiers deliver superior audio signal amplification for outstanding audio performance. The LME49740 combines extremely low voltage noise density ($2.7nV/\sqrt{HZ}$) with vanishingly low THD+N (0.00003%) to easily satisfy the most demanding audio applications. To ensure that the most challenging loads are driven without compromise, the LME49740 has a high slew rate of $\pm 20V/\mu$ s and an output current capability of ± 26 mA. Further, dynamic range is maximized by an output stage that drives $2k\Omega$ loads to within 1V of either power supply voltage and to within 1.4V when driving 600 Ω loads.

The LME49740's outstanding CMRR(120dB), PSRR(120dB), and V_{OS} (0.1mV) give the amplifier excellent operational amplifier DC performance.

The LME49740 has a wide supply range of $\pm 2.5V$ to $\pm 17V$. Over this supply range the LME49740's input circuitry maintains excellent common-mode and power supply rejection, as well as maintaining its low input bias current. The LME49740 is unity gain stable. The Audio Operational Amplifier achieves outstanding AC performance while driving complex loads with values as high as 100pF.

The LME49740 is available in 14–lead narrow body SOIC and 14–lead plastic DIP. Demonstration boards are available for each package.

Key Specifications

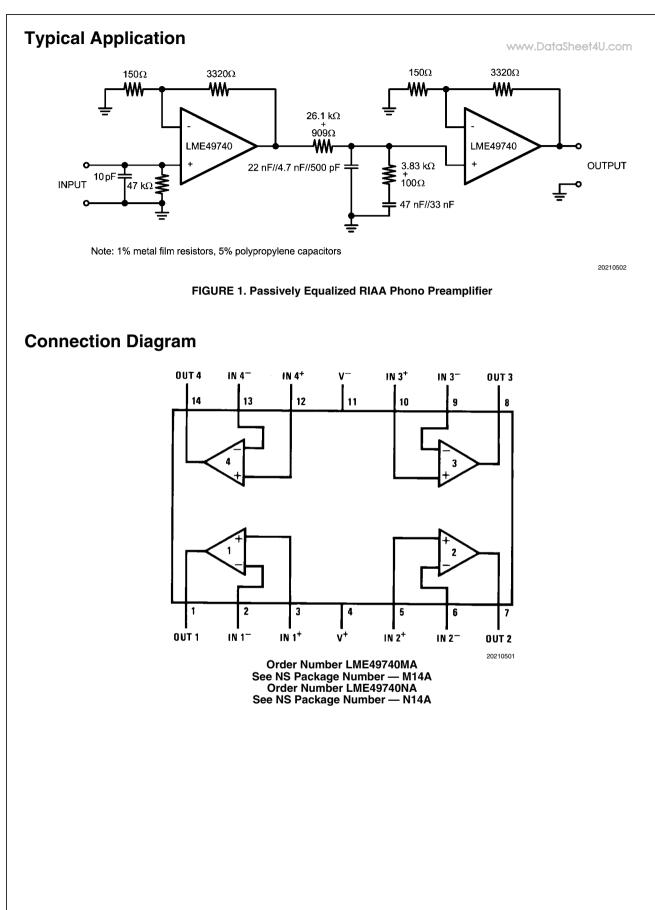
- Power Supply Voltage Range
- THD+N ($A_V = 1$, $V_{OUT} = 3V_{RMS}$, $f_{IN} = 1kHz$)
 - $R_L = 2k\Omega$
- R_L = 600Ω
- Input Noise Density 2.7nV/√Hz (typ)
- Slew Rate
- Gain Bandwidth Product
- Open Loop Gain (R_L = 600Ω)
- Input Bias Current
 10nA (typ)
- Input Offset Voltage 0.1mV (typ)
- DC Gain Linearity Error

Features

- Easily drives 600Ω loads
- Optimized for superior audio signal fidelity
- Output short circuit protection
- PSRR and CMRR exceed 120dB (typ)
- SOIC and DIP packages

Applications

- Ultra high quality audio amplification
- High fidelity preamplifiers
- High fidelity multimedia
- State of the art phono pre amps
- High performance professional audio
- High fidelity equalization and crossover networks
- High performance line drivers
- High performance line receivers
- High fidelity active filters



Absolute Maximum Ratings (Notes 1, 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Distributors for availability a		Thermal Resistance		
Power Supply Voltage		θ _{JA} (MA)	107°C/W	
$(V_{S} = V^{+} - V^{-})$	36V	θ _{JA} (NA)	74°C/W	
Storage Temperature	–65°C to 150°C	Temperature Range		
Input Voltage	(V-) - 0.7V to (V+) + 0.7V	$T_{MIN} \le T_A \le T_{MAX}$	–40°C ≤ T _A ≤ 85°C	
Output Short Circuit (Note 3)	Continuous	Supply Voltage Range	±2.5V ≤ V _S ≤ ± 17V	
Power Dissipation	Internally Limited		5	

ESD Susceptibility (Note 4)

ESD Susceptibility (Note 5)

(Notes 1, 2) The following specifications apply for V_S = ±15V, R_L = 2k\Omega, f_{IN} = 1kHz,

Junction Temperature

Electrical Characteristics

and $T_A = 25C$, unless otherwise specified.

	Parameter	Conditions	LME	LME49740	
Symbol			Typical	Typical Limit	
-			(Note 6)	(Notes 7, 8)	(Limits)
		$A_V = 1, V_{OUT} = 3V_{RMS}$			% (max)
THD+N	Total Harmonic Distortion + Noise	$R_L = 2k\Omega$	0.00003		% (max)
		R _L = 600Ω	0.00003	0.00009	. ,
IMD	Intermodulation Distortion	A _V = 1, V _{OUT} = 3V _{RMS} Two-tone, 60Hz & 7kHz 4:1	0.00005		% (max)
GBWP	Gain Bandwidth Product		55	45	MHz (min)
SR	Slew Rate		±20	±15	V/µs (min)
FPBW	Full Power Bandwidth	$V_{OUT} = 1V_{P.P}, -3dB$ referenced to output magnitude at f = 1kHz	10		MHz
t _s	Settling time	$A_V = 1$, 10V step, $C_L = 100 pF$ 0.1% error range	1.2		μs
	Equivalent Input Noise Voltage	f _{BW} = 20Hz to 20kHz	0.34	0.65	-
e _n	Equivalent Input Noise Density	f = 1kHz	2.7	4.7	1
on		f = 10Hz	6.4		
:	Current Noise Density	f = 1kHz	1.6		pA/√Hz
i _n		f = 10Hz	3.1		pA / √Hz
V _{OS}	Offset Voltage		±0.1	±0.7	mV (max)
ΔV _{OS} /ΔTemp	Average Input Offset Voltage Drift vs Temperature	40°C ≤ T _A ≤ 85°C	0.2		μV/°C
PSRR	Average Input Offset Voltage Shift vs Power Supply Voltage	$\Delta V_{\rm S} = 20V$ (Note 9)	120	110	dB (min)
190	Channel-to-Channel Isolation	f _{IN} = 1kHz	118		% (max) MHz (min V/μs (min MHz μs μV _{RMS} nV/√Hz pA/√Hz pA/√Hz mV (max) μV/°C dB (min) dB nA (max) nA/°C
ISO _{CH-CH}		f _{IN} = 20kHz	112		dB
I _B	Input Bias Current	V _{CM} = 0V	10	72	nA (max)
ΔI _{OS} /ΔTemp	Input Bias Current Drift vs Temperature	–40°C ≤ T _A ≤ 85°C	0.1		nA/°C
I _{os}	Input Offset Current	$V_{CM} = 0V$	11	65	nA (max)
V _{IN-CM}	Common-Mode Input Voltage Range		+14.1 -13.9	(V+)-2.0 (V-)+2.0	. ,
CMRR	Common-Mode Rejection	-10V <v<sub>CM<10V</v<sub>	120	110	dB (min)
7	Differential Input Impedance		30		kΩ
Z _{IN}	Common Mode Input Impedance	-10V <v<sub>CM<10V</v<sub>	1000		MΩ
		-10V <v<sub>OUT<10V, R_L = 600Ω</v<sub>	140		dB (min)
A _{VOL}	Open Loop Voltage Gain	$-10V < V_{OUT} < 10V, R_{L} = 2k\Omega$	140		
		-10V <v<sub>OUT<10V, R_L = 10kΩ</v<sub>	140	125	dB (min)

2000V

150°C

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	Parameter	Conditions	LME	LME49740	
Symbol			Typical	Typical Limit	
			(Note 6)	(Notes 7, 8)	(Limits)
		R _L = 600Ω	±13.6	±12.5	V (min)
V _{OUTMAX}	Maximum Output Voltage Swing	$R_L = 2k\Omega$	±14.0		V (min)
		$R_L = 10k\Omega$	±14.1		V (min)
I _{OUT}	Output Current	$R_{L} = 600\Omega, V_{S} = \pm 17V$	±26	±23	mA (min)
	Short Circuit Current		+30		mA
OUT-CC			-38		mA
		f _{IN} = 10kHz			
R _{OUT}	Output Impedance	Closed-Loop	0.01		Ω
		Open-Loop	13		Ω
CLOAD	Capacitive Load Drive Overshoot	100pF	16		%
I _S	Total Quiescent Current	I _{OUT} = 0mA	18.5	20	mA (max

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur.

Note 2: Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 3: Amplifier output connected to GND, any number of amplifiers within a package.

Note 4: Human body model, 100pF discharged through a 1.5k $\!\Omega$ resistor.

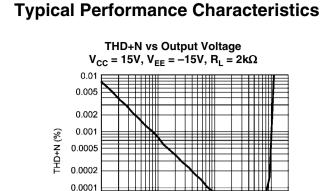
Note 5: Machine Model ESD test is covered by specification EIAJ IC-121-1981. A 200pF cap is charged to the specified voltage and then discharged directly into the IC with no external series resistor (resistance of discharge path must be under 50Ω).

Note 6: Typical specifications are specified at +25 $^{\circ}$ C and represent the most likely parametric norm.

Note 7: Tested limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 8: Datasheet min/max specification limits are guaranteed by design, test, or statistical analysis.

Note 9: PSRR is measured as follows: V_{OS} is measured at two supply voltages, ±5V and ±15V. PSRR = |20log($\Delta V_{OS}/\Delta V_{S}$)|.



100m

1

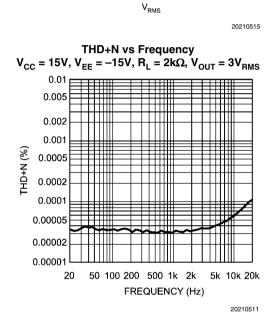
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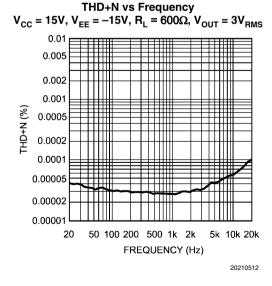
0.00005

0.00002

0.00001

10m

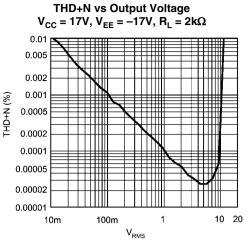




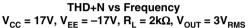


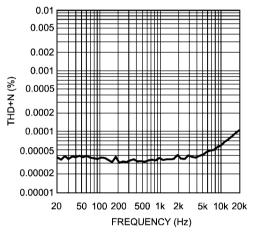
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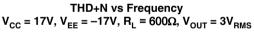


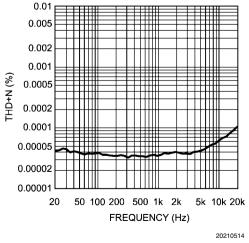
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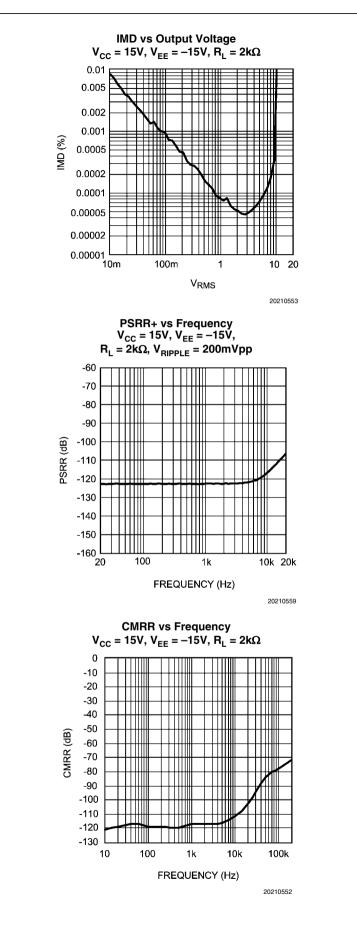


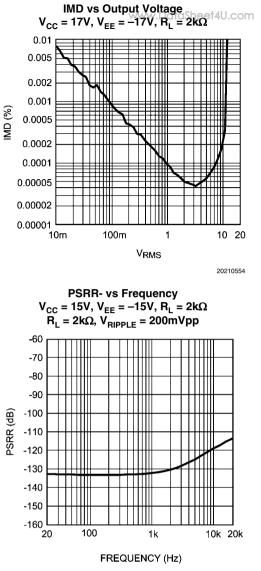


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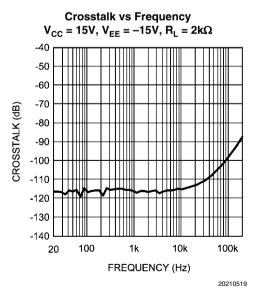




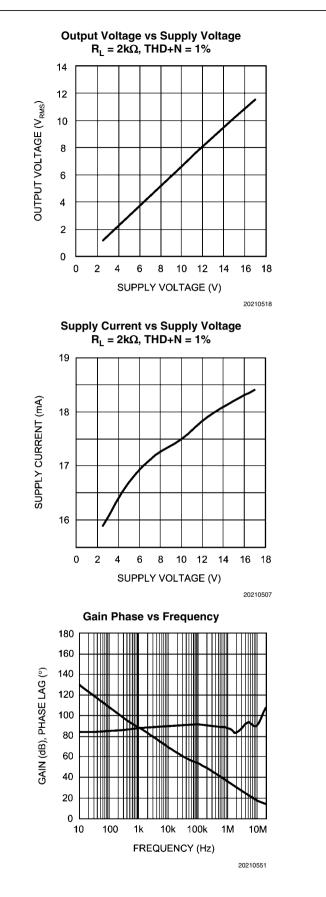


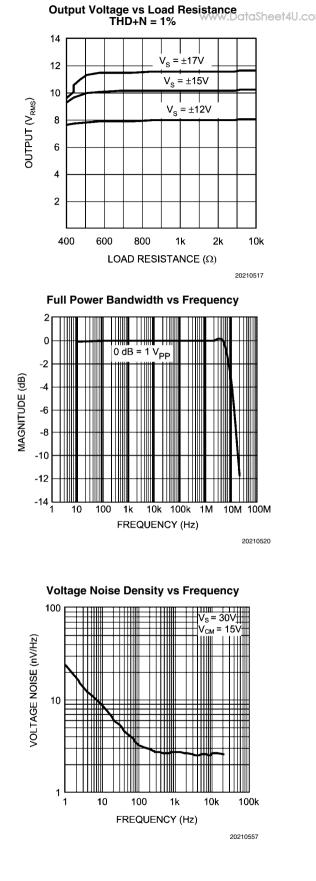


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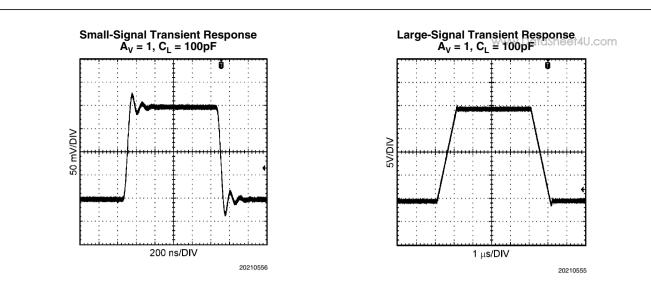


LME49740









Application Information

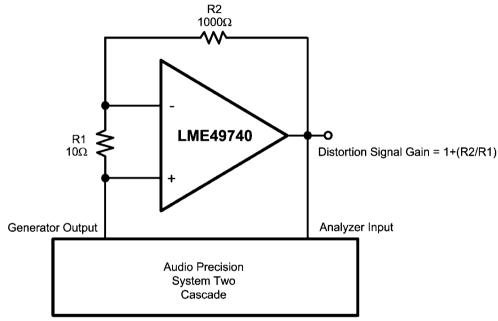
DISTORTION MEASUREMENTS

The vanishingly low residual distortion produced by LME49740 is below the capabilities of all commercially available equipment. This makes distortion measurements just slightly more difficult than simply connecting a distortion meter to the amplifier's inputs and outputs. The solution, however, is quite simple: an additional resistor. Adding this resistor extends the resolution of the distortion measurement equipment.

The LME49740's low residual distortion is an input referred internal error. As shown in Figure 2, adding the 10Ω resistor connected between the amplifier's inverting and non-inverting

inputs changes the amplifier's noise gain. The result is that the error signal (distortion) is amplified by a factor of 1011/Al-co though the amplifier's closed-loop gain is unaltered, the feedback available to correct distortion errors is reduced by 101, which means that measurement resolution increases by 101. To ensure minimum effects on distortion measurements, keep the value of R1 low as shown in Figure 2.

This technique is verified by duplicating the measurements with high closed loop gain and/or making the measurements at high frequencies. Doing so produces distortion components that are within the measurement equipment's capabilities. This datasheet's THD+N and IMD values were generated using the above described circuit connected to an Audio Precision System Two Cascade.



Actual Distortion = AP Value/100

20210562

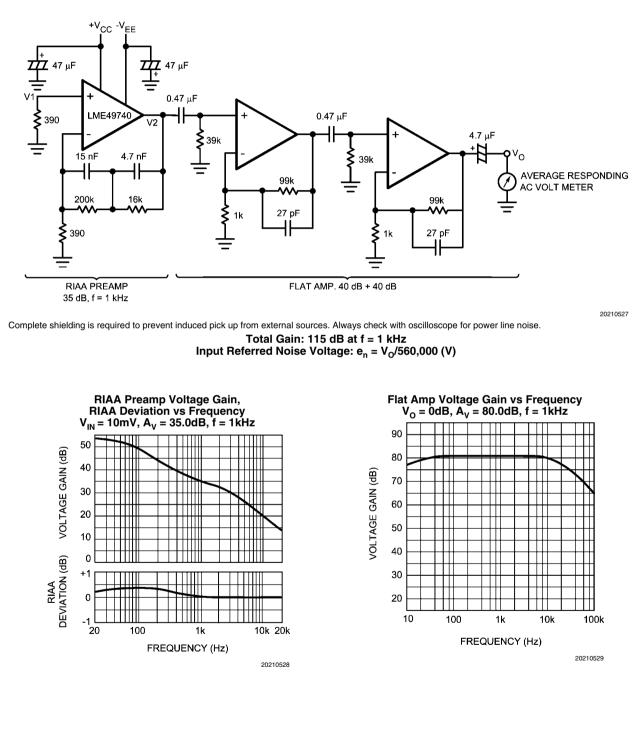
FIGURE 2. THD+N and IMD Distortion Test Circuit

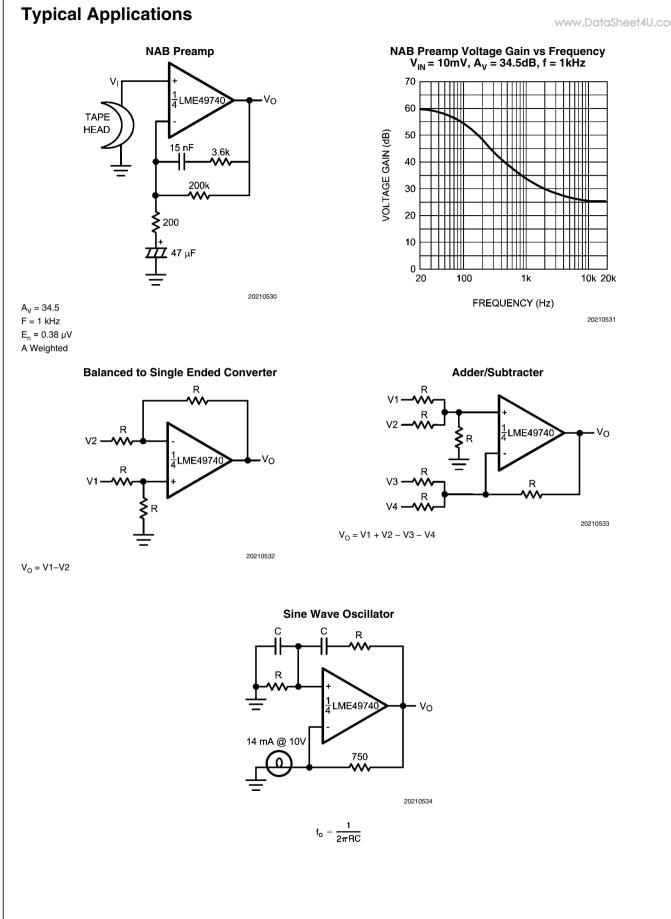
Application Hints

The LME49740 is a high speed op amp with excellent phase margin and stability. Capacitive loads up to 100pF will cause little change in the phase characteristics of the amplifiers and are therefore allowable.

Capacitive loads greater than 100pF must be isolated from the output. The most straightforward way to do this is to put a resistor in series with the output. This resistor will also prevent excess power dissipation if the output is accidentally shorted.

Noise Measurement Circuit





11

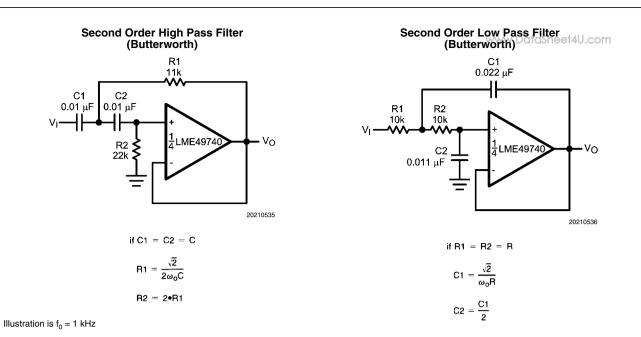
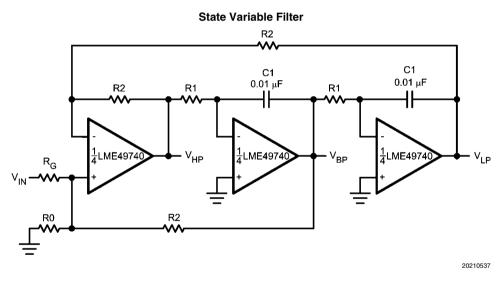
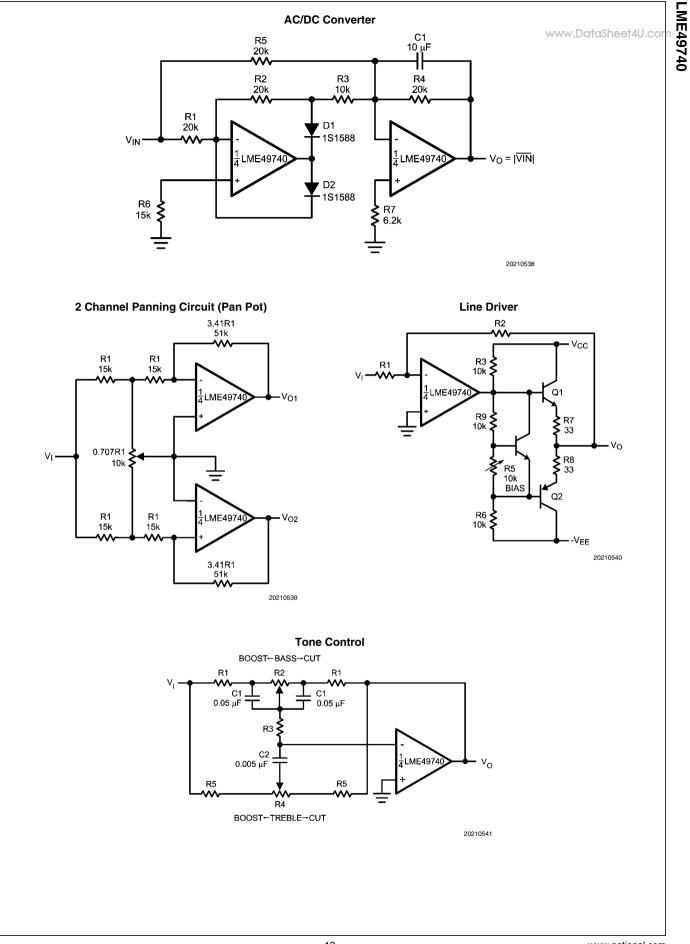
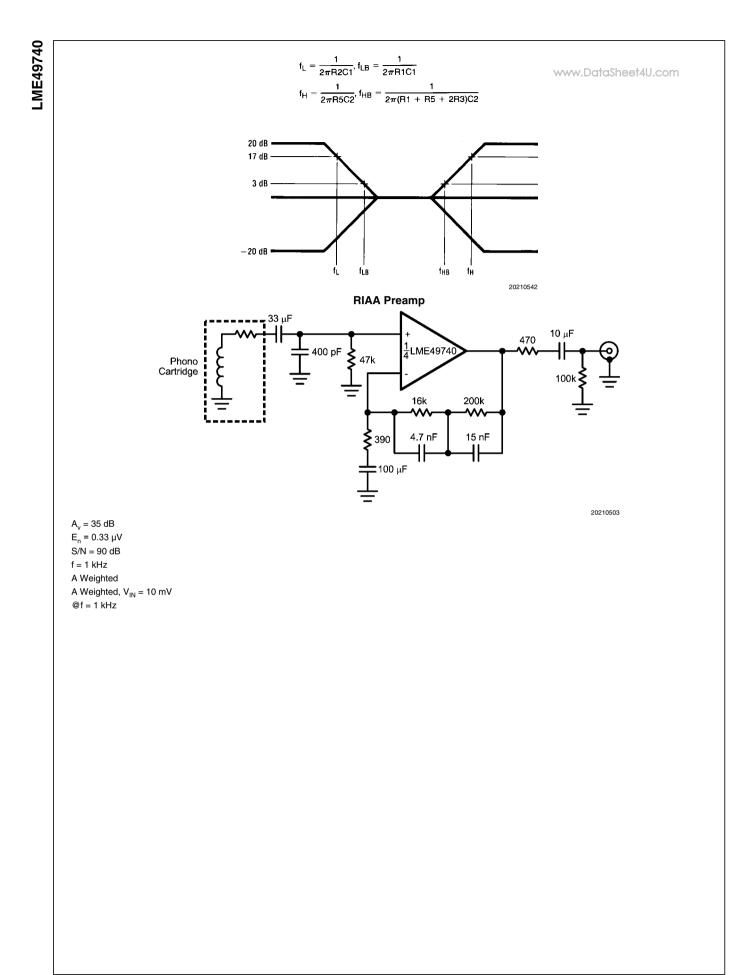


Illustration is $f_0 = 1 \text{ kHz}$



 $f_0 = \frac{1}{2\pi C 1 R 1}, Q = \frac{1}{2} \left(1 + \frac{R2}{R0} + \frac{R2}{RG} \right), A_{BP} = QA_{LP} = QA_{LH} = \frac{R2}{RG}$





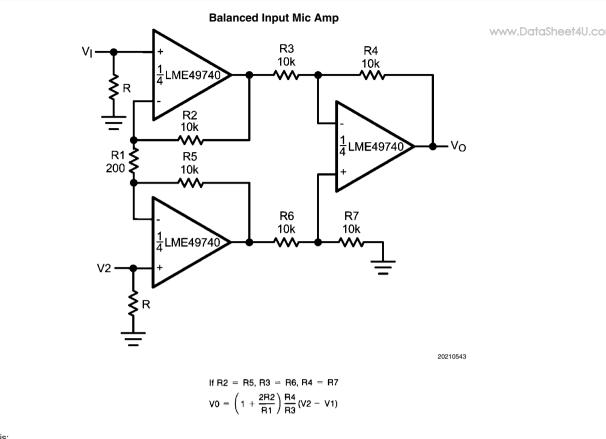


Illustration is: V0 = 101(V2 - V1)

10 Band Graphic Equalizer 20k BOOST CUT f01 f0₂ C2 R2 f03 -3k 1 LME49740 ٧o V C1 f04 f05 3k 1 4LME497 **≶** R1 f0₆ I f07 f08 f0g f0₁₀ 20210544

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fo (Hz)	C ₁	C ₂	R ₁	R ₂
32	0.12µF	4.7µF	75kΩ	500Ω
64	0.056µF	3.3µF	68kΩ	510Ω
125	0.033µF	1.5µF	62kΩ	510Ω
250	0.015µF	0.82µF	68kΩ	470Ω
500	8200pF	0.39µF	62kΩ	470Ω
1k	3900pF	0.22µF	68kΩ	470Ω
2k	2000pF	0.1µF	68kΩ	470Ω
4k	1100pF	0.056µF	62kΩ	470Ω
8k	510pF	0.022µF	68kΩ	510Ω
16k	330pF	0.012µF	51kΩ	510Ω

Note 10: At volume of change = $\pm 12 \text{ dB}$

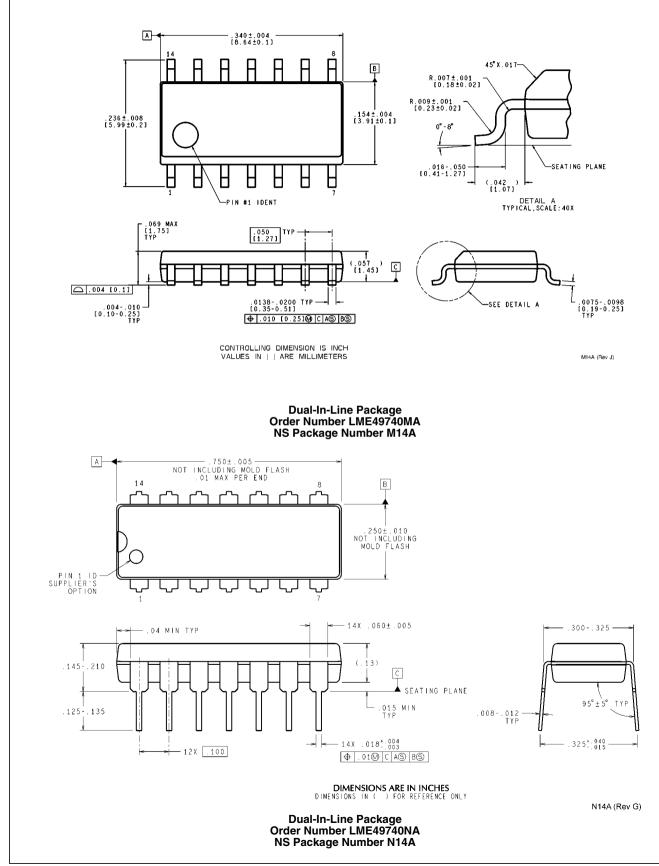
Q = 1.7

Reference: "AUDIO/RADIO HANDBOOK", National Semiconductor, 1980, Page 2-61

Revision History www.DataSheet4U.cor					
Rev	Date	Description			
1.0	02/28/07	Initial WEB release.			

Physical Dimensions inches (millimeters) unless otherwise noted

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